

## 五、論文著述：

1. 請詳列個人最近五年內發表之學術性著作，包括：期刊論文、專書及專書論文、研討會論文、技術報告及其他等，並請依各類著作之重要性自行排列先後順序。
2. 各類著作請按發表時間先後順序填寫。各項著作請務必依作者姓名（按原出版之次序，通訊作者請加註\*。）、出版年、月份、題目、期刊名稱（專書出版社）、起迄頁數之順序填寫，被接受刊登尚未正式出版者請附被接受函，
3. 若期刊屬於 SCI、EI、SSCI 或 A&HCI 等時，請註明；若著作係經由國科會補助之研究計畫所產生，請於最後填入相關之國科會計畫編號。

A) Referred Journal 期刊論文 共計 113 篇 (104 篇 SCI/SSCI; 6 篇 EI; 3 篇國際期刊)

(2010/8~迄今) 共計57篇 (53篇為SCI/SSCI; 4篇EI)

1. F. K. Wang\* and Y. Tamirat, accepted 2015 (6), Process yield for multivariate linear profiles with one-sided specification limits, *Quality and Reliability Engineering International*, SCI, doi:10.1002/qre.1834
2. F. K. Wang\* and Y. Tamirat, accepted 2015 (6), Multiple comparisons with the best for supplier selection with linear profiles, *International Journal of Production Research*, SCI
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4. F. K. Wang\*, accepted 2015 (3), Variables sampling plan for resubmitted lots in a process with linear profiles, *Quality and Reliability Engineering International*, SCI, doi:10.1002/qre.1812
5. F. K. Wang\* and Y. Tamirat, accepted 2015 (1), Multiple comparisons with the best for process selection for linear profiles with one-sided specifications, *Quality and Reliability Engineering International*, SCI, doi:10.1002/qre.1784
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7. F. K. Wang\*, accepted 2014 (9), Supplier selection for multiple linear profiles with one-sided specifications, *Quality and Reliability Engineering International*, SCI, doi: 10.1002/qre.1746
8. F. K. Wang\*, accepted 2014 (8), The difference test statistic for two suppliers with linear profiles, *Quality and Reliability Engineering International*, SCI, doi:

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9. F. K. Wang\* and Y. C. Lu, accepted 2014 (6), A new model for repairable systems with non-monotone intensity function, *Quality and Reliability Engineering International*, SCI, doi: 10.1002/qre.1690
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14. F. K. Wang\*, 2015 (6), Measuring the process yield for circular profiles, *Quality and Reliability Engineering International*, 31(4), 579-588. SCI, doi: 10.1002/qre.1614
15. F. K. Wang\* and Y. Tamirat, 2015 (6), Lower confidence bound for process-yield index  $Sp_k$  with autocorrelated process data, *Quality Technology and Quantitative Management*, 12(2), 251-265, SCI
16. S. H. Sheu, H. N. Tsai, T. S. Hsu and F. K. Wang, 2015 (6), Optimal number of minimal repairs before replacement of a deteriorating system with inspections, *International Journal of Systems Science*, 46(8), 1367-1379, SCI, doi:10.1080/00207721.2013.822125
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21. F. K. Wang\*, 2014 (10), Using BBPSO algorithm to estimate the Weibull parameters with censored data, *Communications in Statistics – Simulation and Computation*, 43(10), 2614-2627. SCI, doi:10.1080/03610918.2012.762386
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submitted paper:

1. Using the design for Six Sigma approach with TRIZ for new product development, *C&IE*, SCI
2. Evaluating the efficiency of green vehicles, *International Journal of Green Energy*, SCI

B) Chapter in Book & Book:

1. Y. Hsiao and F. K. Wang, *Forecasting analysis for global copper clad laminate market*, Lambert Academic Publishing, 2011, ISBN: 978-3-8443-1646-9.
2. F. K. Wang, Comparison of multivariate process capability indices, in *Encyclopedia of Statistics in Quality and Reliability*, Ruggeri, F., Kenett, R. and Faltin, F. W. (eds). John Wiley & Sons Ltd, Chichester, UK, pp. 1218-1224, 2007.

C) Conference Paper:

1. F. K. Wang, Y. C. Lu, Predicting failure rate for desktop personal computers, *The 3rd International Scientific Conference on Engineering and Applied Sciences (ISCEAS 2015)*, Okinawa, Japan, July 29-31, 2015.
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- 3 F. K. Wang, Y. C. Lu, Bathtub type of failure intensity model for repairable systems, 中國工業工程學會103年度年會暨學術研討會, New Taipei City, Taiwan, December 6, 2014.
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  - 10 朱道鵬、葉青潭、王福琨, 應用六標準差設計於無線通訊局端設備的產品開發, 2011國際品質管理研討會(中華民國品質學會第四十七屆年會), 彰化, November 5, 2011.
  - 11 Y. Hsiao and F. K. Wang, Forecasting analysis for global copper clad laminate market, 3<sup>rd</sup> International Conference on Data Mining and Intelligent Information Technology, Macau, China, October 24-26, 2011.
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